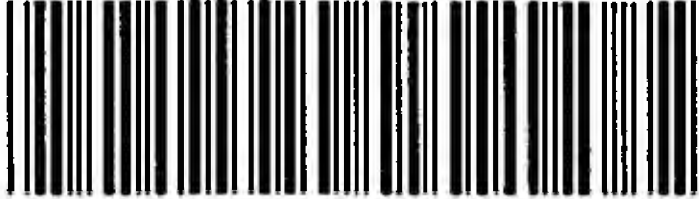


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/854,463	HANNUKSELA ET AL.	
	Examiner	Art Unit	
	Erick Rekstad	2613	

SEARCHED			
Class	Subclass	Date	Examiner
375	240.27	7/21/04	ER
	240.01	5/27/05	
	240.13		
	240.25	11/14/05	
386	117	7/21/04 5/27/05	ER
382	232	7/21/04 5/27/05	ER
348	14.01	7/21/04 5/27/05	ER
348	14.02	7/21/04 5/27/05	ER

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	240.25	5/27/2005	ER
375	240.27	11/14/2005	ER

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE: error <and> concealment <and> video	5/27/2005	ER
IEEE, ACM Digital Library, CiteSeer, Optics Information Database search for (h.263 and supplemental enhancement)	11/14/2005	ER
keyword search	7/21/2004	ER
keyword search	5/27/2005	ER
keyword search	11/14/2005	ER